

ISO/IEC 30192:2021 (E)

Information technology — Digitally recorded media for information interchange and storage — 120 mm Single Layer (25,0 Gbytes per disk) and Dual Layer (50,0 Gbytes per disk) BD Rewritable disk

Contents

	Foreword
	Introduction
1	Scope
2	Normative references
3	Terms and definitions
4	Symbol and abbreviated terms
5	Conformance
5.1	Optical disk
5.2	Generating system
5.3	Receiving system
5.4	Compatibility statement
6	Conventions and notations
6.1	Levels of grouping
6.2	Representation of numbers
6.3	Integer calculus
7	General descriptions of disk
8	General requirements
8.1	Environments
8.1.1	Test environment
8.1.1.1	General
8.1.1.2	Test conditions for sudden changes in operating environment
8.1.2	Operating environment
8.1.3	Storage environment
8.1.3.1	General
8.1.3.2	Climatic storage tests
8.1.4	Transportation
8.1.4.1	General
8.1.4.2	Packaging
8.1.4.2.1	General
8.1.4.2.2	Temperature and humidity
8.1.4.2.3	Impact loads and vibrations
8.2	Safety requirements
8.3	Flammability
9	Reference drive
9.1	General
9.2	Environmental conditions
9.3	Optical system
9.4	Optical beam
9.5	HF read channel
9.6	Radial PP read channel
9.7	Disk clamping
9.8	Rotation of the disk and measurement velocity

- 9.9 Normalized servo transfer function
- 9.10 Measurement velocity and reference servo for axial tracking
- 9.11 Measurement velocity and reference servo for radial tracking

10 Dimensional characteristics

- 10.1 General
- 10.2 Disk reference planes and reference axis
- 10.3 Overall dimensions
- 10.4 First transition area
- 10.5 Protection ring
- 10.6 Clamping zone
- 10.7 Second transition area
- 10.8 Information area
 - 10.8.1 General
 - 10.8.2 Subdivisions of information zone on SL disk
 - 10.8.3 Subdivisions of information zone on DL disks
- 10.9 Rim area

11 Mechanical characteristics

- 11.1 Mass
- 11.2 Moment of inertia
- 11.3 Dynamic imbalance
- 11.4 Axial runout
- 11.4.1 General
- 11.4.2 Residual axial tracking error
- 11.5 Radial runout
- 11.5.1 General
- 11.5.2 Residual radial tracking error on SL disks
- 11.5.3 Residual radial tracking error on DL disks
- 11.6 Durability of cover layer
- 11.6.1 Impact resistance of cover layer
- 11.6.2 Scratch resistance of cover layer
- 11.6.3 Repulsion of fingerprints by cover layer

12 Optical characteristics in information area

- 12.1 General
- 12.2 Refractive index of transmission stacks (TS)
- 12.3 Thickness of transmission stack(s)
 - 12.3.1 Thickness of transmission stack of SL disks
 - 12.3.2 Thickness of transmission stack of DL disks
- 12.4 Reflectivity
 - 12.4.1 Reflectivity of recording layer of SL disks
 - 12.4.2 Reflectivity of recording layer of DL disks
- 12.5 Birefringence
- 12.6 Angular deviation

13 Data format

- 13.1 General
- 13.2 Data frames
- 13.3 Error detection code (EDC)
- 13.4 Scrambled data frame
- 13.5 Data block
- 13.6 LDC block
- 13.7 LDC code words
- 13.8 LDC cluster
- 13.8.1 General
- 13.8.2 First interleave step
- 13.8.3 Second interleaving step
- 13.9 Addressing and control data
- 13.9.1 General
- 13.9.2 Address units
 - 13.9.2.1 General
 - 13.9.2.2 Bytes assignments for address fields
 - 13.9.2.3 Address unit numbers

- 13.9.2.4 Assignments for flag bit
- 13.9.2.5 Usage of status bits Sai,j
- 13.9.3 User control data
- 13.9.4 Byte/bit assignments for user control data
- 13.10 Access block
- 13.11 BIS block
- 13.12 BIS code words
- 13.13 BIS cluster
- 13.14 ECC cluster
- 13.15 Recording frames
- 13.16 Physical cluster
- 13.17 17PP modulation for recordable data
- 13.17.1 General
- 13.17.2 Bit conversion rules
- 13.17.3 dc-control procedure
- 13.17.4 Frame sync
- 13.18 Modulation and NRZI conversion

14 Physical data allocation and linking

- 14.1 General
- 14.2 Recording unit block (RUB)
- 14.2.1 General
- 14.2.2 Data run-in
- 14.2.2.1 General
- 14.2.2.2 Content of Guard_1 field
- 14.2.2.3 Automatic power control (APC)
- 14.2.2.4 Content of PrA field
- 14.2.3 Data run-out
- 14.2.3.1 General
- 14.2.3.2 Content of PoA field
- 14.2.3.3 Content of Guard_2 field
- 14.2.4 Guard_3 field
- 14.2.4.1 General
- 14.2.4.2 Automatic power control (APC)
- 14.3 Locating data relative to wobble addresses
- 14.3.1 General
- 14.3.2 Start position shift (SPS)

15 Track format

- 15.1 General
- 15.2 Track shape
- 15.3 Track path
- 15.4 Track pitch
- 15.4.1 Track pitch in BCA zone
- 15.4.2 Track pitch in embossed HFM areas
- 15.4.3 Track pitch in rewritable areas
- 15.4.4 Track pitch between embossed HFM area and rewritable area
- 15.5 Track layout of HFM groove
- 15.5.1 General
- 15.5.2 Data format
- 15.5.2.1 Data frame
- 15.5.2.2 Scrambled data frame
- 15.5.2.3 Data block
- 15.5.2.4 LDC block
- 15.5.2.5 Interleaving
- 15.5.3 Addressing and control data
- 15.5.3.1 General
- 15.5.3.2 Address field
- 15.5.3.3 User control data
- 15.5.3.4 BIS code words
- 15.5.3.5 BIS cluster
- 15.5.4 Recording frames
- 15.5.4.1 General
- 15.5.4.2 Modulation

- 15.5.4.3 Frame sync
- 15.6 Track layout of wobbled groove(s)
- 15.6.1 General
- 15.6.2 Modulation of wobbles
- 15.6.2.1 General
- 15.6.2.2 MSK-cos modulation
- 15.6.2.3 HMW modulation
- 15.7 ADIP information
- 15.7.1 General
- 15.7.2 ADIP unit types
- 15.7.3 ADIP Word structure
- 15.7.4 ADIP Data structure
- 15.7.4.1 General
- 15.7.4.2 ADIP information bit assignments
- 15.7.4.3 Relation between physical ADIP addresses on layer L0 and layer L1
- 15.7.5 ADIP error correction
- 15.8 Disk information in ADIP aux frame
- 15.8.1 General
- 15.8.2 Error protection for disk information aux frames
- 15.8.3 Disk information data structure
- 15.8.3.1 General
- 15.8.3.2 General definitions for DI unit
- 15.8.3.3 Definitions for DI format 1(N-1 write strategy A)
- 15.8.3.4 Definitions for DI format 2 (N-1 write strategy B)
- 15.8.3.5 Definitions for DI format 3 (N/2 write strategy)
- 15.8.3.6 Write strategy requirements
- 15.8.3.7 Usage of DI units for write strategies

16 General description of information zone

- 16.1 General
- 16.2 Format of information zone on single-layer disk
- 16.3 Format of information zone on dual-layer disk

17 Layout of rewritable area of information zone

18 Inner zone

- 18.1 General
- 18.2 Permanent information and control data (PIC) zone
- 18.2.1 General
- 18.2.2 Content of PIC zone
- 18.2.3 Emergency brake
- 18.3 Rewritable area of inner zone(s)
- 18.3.1 Protection zone 2
- 18.3.2 INFO 2/Reserved 8
- 18.3.3 INFO 2/Reserved 7
- 18.3.4 INFO 2/Reserved 6
- 18.3.5 INFO 2/Reserved 5
- 18.3.6 INFO 2/PAC 2
- 18.3.7 INFO 2/DMA 2
- 18.3.8 INFO 2/Control data 2
- 18.3.9 INFO 2/Buffer 2
- 18.3.10 OPC/Test zone
- 18.3.11 Reserved
- 18.3.12 INFO1/Buffer 1
- 18.3.13 INFO 1/Drive area (optional)
- 18.3.13.1 General
- 18.3.13.2 Format of drive-specific information
- 18.3.14 INFO 1/Reserved 3
- 18.3.15 INFO 1/Reserved 2
- 18.3.16 INFO 1/Reserved 1
- 18.3.17 INFO 1/DMA 1
- 18.3.18 INFO1/Controle data 1
- 18.3.19 INFO1/PAC 1

- 19 Data zone
- 20 Outer zone(s)
 - 20.1 General
 - 20.2 INFO 3/Buffer 4
 - 20.3 INFO 3/DMA 3
 - 20.4 INFO 3/Control data 4
 - 20.5 Angular buffer
 - 20.6 INFO 4/DMA 4
 - 20.7 INFO 4/Control data 4
 - 20.8 INFO 4 / Buffer 6
 - 20.9 Protection zone 3
- 21 Physical access control clusters
 - 21.1 General
 - 21.2 Layout of PAC zones
 - 21.3 General structure of PAC clusters
 - 21.4 Primary PAC cluster (mandatory)
 - 21.5 Disk write-protect PAC cluster (optional)
 - 21.6 IS1 and IS2 PAC clusters
- 22 Disk management
 - 22.1 General
 - 22.2 Disk management structure (DMS)
 - 22.2.1 General
 - 22.2.2 Disk definition structure (DDS)
 - 22.2.3 Defect list (DFL)
 - 22.2.4 Defect list header (DLH)
 - 22.2.5 List of defects
 - 22.2.6 DFL entries
- 23 Assignment of logical sector numbers (LSNs)
- 24 Characteristics of grooved areas
- 25 Method of testing for grooved area
 - 25.1 General
 - 25.2 Environment
 - 25.3 Reference drive
 - 25.3.1 General
 - 25.3.2 Read power
 - 25.3.3 Read channels
 - 25.3.4 Tracking requirements
 - 25.3.5 Scanning velocity
 - 25.4 Signals
- 26 Signals from HFM grooves
 - 26.1 Push-pull signal
 - 26.2 HFM wobble signal
 - 26.3 Jitter of HFM signal
- 27 Signals from wobbled groove(s)
 - 27.1 Phase depth
 - 27.2 Push-pull signal
 - 27.3 Wobble signal
 - 27.3.1 General
 - 27.3.2 Measurement of INWS
 - 27.3.3 Measurement of wobble CNR
 - 27.3.4 Measurement of harmonic distortion requirements
- 28 Characteristics of recording layer
- 29 Method of testing for recording layer

29.1	General
29.2	Environment
29.3	Reference drive
29.3.1	General
29.3.2	Read power
29.3.3	Read channels
29.3.4	Tracking requirements
29.3.5	Scanning velocities
29.4	Write conditions
29.4.1	Write-pulse waveform
29.4.2	Write powers
29.4.3	Write conditions for jitter measurement
29.4.4	Write conditions for cross-erase measurement
29.4.5	Write conditions for inter-velocity overwrite measurements
29.5	Definition of signals
30	Signals from recorded areas
30.1	HF signals
30.2	Modulated amplitude
30.3	Reflectivity modulation product
30.4	Asymmetry
30.5	Jitter
30.6	Cross-erase
30.7	Inter-velocity overwrite
30.8	Read stability
31	Local defects
32	Characteristics of user data
33	Method of testing for user data
33.1	General
33.2	Environment
33.3	Reference drive
33.3.1	General
33.3.2	Read power
33.3.3	Read channels
33.3.4	Error correction
33.3.5	Tracking requirements
33.3.6	Scanning velocities
33.4	Error signals
34	Minimum quality of recorded information
34.1	Random symbol error rate
34.2	Maximum burst errors
34.3	User-written data
35	BCA
Annex A (normative) Thickness of transmission stacks in case of multiple layers	
A.1	General
A.2	Refractive index n_i of all layers in cover layer and spacer layer
A.3	Thickness variation of the transmission stack
A.4	Example of thickness calculation for SL
Annex B (normative) Measurement of reflectivity	
B.1	General
B.2	Calibration method
B.3	Measuring method
B.3.1	Reflectivity in unrecorded, virgin rewritable areas
B.3.2	Reflectivity in unrecorded, erased rewritable areas
B.3.3	Reflectivity in recorded rewritable areas
Annex C (normative) Measurement of scratch resistance of cover layer	

- C.1 General
- C.2 Taber abrasion test

Annex D (normative) Measurement of repulsion of grime by cover layer

- D.1 General
- D.2 Specifications of stamp
- D.3 Preparation of ink
- D.4 Preparation of ink pad
- D.5 Using ink pad and stamp

Annex E (normative) Measurement of wobble amplitude

- E.1 Measurement methods
- E.2 Calibration of filters

Annex F (normative) Write-pulse waveform for testing

- F.1 General write-pulse waveform
- F.2 N-1 write strategy A
- F.3 N-1 write strategy B
- F.4 N/2 write strategy
- F.5 Definition of pulse widths and rise and fall times

Annex G (normative) Optimum power control (OPC) procedure for disk

- G.1 General
- G.2 Mathematical model for modulation versus power function
- G.3 Procedure for determination of OPC parameters for disk
- G.4 Write-power window

Annex H (normative) HF signal pre-processing for jitter measurements

- H.1 General
- H.2 General implementation of equalizer
- H.3 Conventional Equalizer circuit
- H.4 Limit equalizer circuit
- H.5 Specifications of supporting circuits
- H.5.1 Amplifiers and filters
- H.5.2 Open-loop transfer function for PLL
- H.5.3 Slicer
- H.6 Condition for measurement
- H.7 Jitter measurement

Annex I (normative) Measurement procedure

- I.1 General
- I.2 Initial adjustments of reference drive
- I.3 Jitter measurement
- I.4 Modulated amplitude measurements
- I.5 Measurements of resolution I2pp/I8pp and I3pp/I8pp
- I.5.1 Method for measuring I2pp and I8pp
- I.5.2 I3pp/I8pp, I8pp/I8H and asymmetry measurement procedure
- I.6 Tracking error signal measurements (VPPnorm measurement procedure)
- I.7 Residual error of axial tracking measurement procedure
- I.8 Residual error of radial tracking measurement procedure
- I.9 Random SER measurement

Annex J (informative) Measurement of birefringence

- J.1 Principle of measurement
- J.2 Measurements conditions
- J.3 Example of measurement procedure
- J.4 Interchangeability of measuring results

Annex K (informative) Measurement of thickness of cover layer and spacer layer

- K.1 Focusing method
- K.2 Interferometer method

Annex L (informative) Measurement of impact resistance of cover layer

- L.1 General

L.2 Recommendation for drives
L.3 Measurements of impact resistance of cover layer

Annex M (informative) Groove deviation and wobble amplitude

M.1 Relation between normalized wobble signal and wobble amplitude
M.2 Tolerance of normalized wobble signal

Page count: 214